LETTER TO THE EDITOR

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References


Crystallographers


This section is intended to be a series of short paragraphs dealing with the activities of crystallographers, such as their changes of position, promotions, assumption of significant new duties, motions, assumption of significant new duties, sections there are reports on X-ray diffraction analysis (XRD) and X-ray spectrometry (XRS; mainly X-ray fluorescence analysis (XRF)). It is difficult to review all the essential results and ideas contained in this volume, but a short summary will be given here.

Nowadays it is possible to obtain refined values of crystal-structure parameters from powder diffraction data by the Rietveld method, including a least-squares refinement procedure for fitting calculated and observed powder diffraction patterns. An example is given for human tooth enamel. Further, advances in the interpretation of diffraction data from amorphous materials are outlined. Qualitative and quantitative phase analysis, collection of crystallographic data, precision and reproducibility of Guinier powder patterns, and the level of XRD in Europe are discussed. The great importance of continuously scanning position-sensitive detectors in modern XRD work is demonstrated by the ten papers on this topic. Application, use and accuracy of such detectors are described; they are capable now of scanning speeds of several hundred degrees per minute, and

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Structure Reports

Volume 46A of Structure Reports has recently been published. It covers the literature for metals and inorganic compounds for 1980 (464 pages) and costs 153 Netherlands guilders for subscribers with standing orders. The full price for individual copies is 180 guilders but personal subscribers may buy a copy for their own use at 90 guilders. Orders for these publications may be placed direct with the publisher, D. Reidel Publishing Company, PO Box 17, 3300 AA Dorrecht, The Netherlands, or with any bookseller. Trade orders should be sent to Reidel.

Book Reviews

Works intended for notice in this column should be sent direct to the Book Review Editor U. H. Robertson, School of Chemistry, University of Leeds, LS2 9JT, England. As far as practicable books will be reviewed in a country different from that of publication.


During the 29th Denver Conference on Applications of X-ray analysis, 74 papers were read, 56 of which are published in this volume. Following the tradition of the conferences there are reports on X-ray diffraction analysis (XRD) and X-ray spectrometry (XRS; mainly X-ray fluorescence analysis (XRF)). It is difficult to review all the essential results and ideas contained in this volume, but a short summary will be given here.

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